# 1. General description

Hyperfast power diode and Standard reverse recovery power diode in a single TO247 package, intended for use as input rectifier and bypass diode in a PFC application.

## 2. Features and benefits

Hyperfast power diode

- · Low leakage current
- · Low thermal resistance
- Low reverse recovery

Standard recovery diode

- · Low forward voltage drop
- Low leakage current
- High voltage capability
- · High inrush current capability

# 3. Applications

- · Solar inverter
- Continuous Current Mode (CCM) Power Factor Correction (PFC)

## 4. Quick reference data

### Table 1. Quick reference data

Hyperfast	Power Diode						
Symbol	Parameter	Conditions		Values			Unit
$V_{RRM}$	repetitive peak reverse voltage				600		V
$I_{F(AV)}$	average forward current	$\delta$ = 0.5; T <sub>mb</sub> ≤ 122 °C; square-wave pulse Fig. 1a; Fig. 2a; Fig. 3a	,		30		А
I <sub>FSM</sub>	non-repetitive peak	$t_p = 10 \text{ ms}; T_{j(init)} = 25 \text{ °C}; \text{ sine-wave pulse}$	; <u>Fig. 4a</u>		270		А
	forward current	$t_p$ = 8.3 ms; $T_{j(init)}$ = 25 °C; sine-wave pulse	e		300		Α
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static cha	racteristics						
V <sub>F</sub>	forward current	I <sub>F</sub> = 30 A; T <sub>j</sub> = 25 °C; <u>Fig. 6a</u>		-	2	2.75	V
		I <sub>F</sub> = 30 A; T <sub>j</sub> = 150 °C; <u>Fig. 6a</u>		-	1.38	1.8	V
Dynamic	characteristics						
t <sub>rr</sub>	reverse recovery time	$I_F = 1 \text{ A}$ ; $V_R = 30 \text{ V}$ ; $dI_F/dt = 200 \text{ A/}\mu\text{s}$ ; $T_j = 25 \text{ °C}$ ; Fig. 7		-	18	22	ns
		$I_F = 30 \text{ A}; V_R = 200 \text{ V}; dI_F/dt = 200 \text{ A/}\mu\text{s};$ $T_j = 25 \text{ °C}; Fig. 7$		-	35	50	ns
		$I_F = 30 \text{ A}$ ; $V_R = 200 \text{ V}$ ; $dI_F/dt = 200 \text{ A}/\mu\text{s}$ ; $T_j = 125 \text{ °C}$ ; Fig. 7		-	70	-	ns
		$I_F = 30 \text{ A}$ ; $V_R = 400 \text{ V}$ ; $dI_F/dt = 500 \text{ A/}\mu\text{s}$ ; $T_j = 25 \text{ °C}$ ; Fig. 7		-	29	-	ns

Standard	Recovery Diode						
Symbol	Parameter	Conditions		Values			Unit
$V_{RRM}$	repetitive peak reverse voltage				1600		V
$I_{F(AV)}$	average forward current	$δ = 0.5$ ; $T_{mb} \le 121$ °C; square-wave pulse; Fig. 1b; Fig. 2b; Fig. 3b			45		А
I <sub>FSM</sub>	non-repetitive peak	$t_p$ = 10 ms; $T_{J(init)}$ = 25 °C; sine-wave pulse; Fig. 4b		475		Α	
	forward current	$t_p$ = 8.3 ms; $T_{j(init)}$ = 25 °C; sine-wave pulse		523		Α	
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static cha	racteristics						
$V_{F}$	forward current	I <sub>F</sub> = 45 A; T <sub>j</sub> = 25 °C; <u>Fig. 6b</u>		-	1.2	1.4	V
		I <sub>F</sub> = 45 A; T <sub>j</sub> = 150 °C; <u>Fig. 6b</u>		-	1.1	1.3	V

# 5. Pinning information

### **Table 2. Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	A1	anode (Hyperfast)		
2	K	cathode		A1
3	A2	anode (Standard)		K
mb	К	mounting base; connected to cathode		sym125

# 6. Ordering information

**Table 3. Ordering information** 

Type number	Package name	Orderable part number	Packing method	Small packing guantity	Package version	Package issue date
WNC3060D45160W	TO247	WNC3060D45160WQ	Tube	30	10101011	02-Jan-2020
					TO247P (P)	31-Mar-2023

# 7. Marking

#### Table 4. Marking codes

Table 4. Marking codes						
Type number	Marking codes					
	Assembly factory: L	Assembly factory: P				
WNC3060D45160W	WNC3060	WNC3060				
	D45160W	D45160W				
	PJLxxxx xx	PJPxxxx xx				

# 8. Limiting values

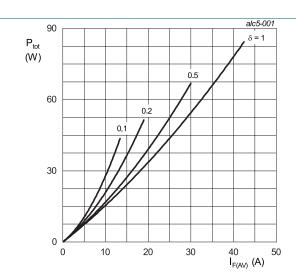
### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Hyperfast	Power Diode			
Symbol	Parameter	Conditions	Values	Unit
$V_{RRM}$	repetitive peak reverse voltage		600	V
$V_{RWM}$	crest working reverse voltage		600	V
$V_R$	reverse voltage	DC	600	V
$I_{F(AV)}$	average forward current	$\delta$ = 0.5; $T_{mb} \le$ 122 °C; square-wave pulse; Fig. 1a; Fig. 2a; Fig. 3a	30	А
I <sub>FRM</sub>	repetitive peak forward current	$\delta$ = 0.5; t <sub>p</sub> = 25 μs; T <sub>mb</sub> ≤ 122 °C; square-wave pulse	60	А
I <sub>FSM</sub>	non-repetitive peak forward current	$t_p$ = 10 ms; $T_{J(init)}$ = 25 °C; sine-wave pulse; Fig. 4a	270	А
		$t_p$ = 8.3 ms; $T_{j(init)}$ = 25 °C; sine-wave pulse	300	А
T <sub>stg</sub>	storage temperature		-55 to 175	°C
T <sub>j</sub>	junction temperature		175	°C

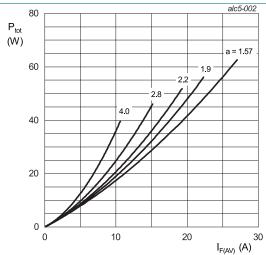
### **Standard Recovery Diode**

Symbol	Parameter	Conditions	Values	Unit
$V_{RRM}$	repetitive peak reverse voltage		1600	V
$V_{\text{RWM}}$	crest working reverse voltage		1600	V
$V_R$	reverse voltage	DC	1600	V
I <sub>F(AV)</sub>	average forward current	$δ = 0.5$ ; $T_{mb} \le 121$ °C; square-wave pulse; Fig. 1b; Fig. 2b; Fig. 3b	45	А
I <sub>FSM</sub>	non-repetitive peak forward current	$t_p$ = 10 ms; $T_{j(init)}$ = 25 °C; sine-wave pulse; Fig. 4b	475	А
		$t_p$ = 8.3 ms; $T_{j(init)}$ = 25 °C; sine-wave pulse	523	Α
T <sub>stg</sub>	storage temperature		-55 to 175	°C
T <sub>j</sub>	junction temperature		150	°C



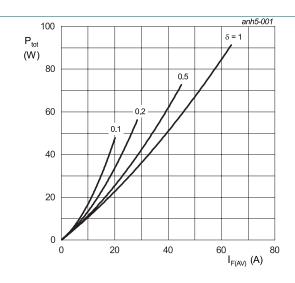
 $I_{F(AV)} = I_{F(RMS)} \times \sqrt{\delta}$ V<sub>o</sub> = 1.403 V; R<sub>s</sub> = 0.0138 Ω

Fig. 1a. Forward power dissipation as a function of average forward current; square waveform; maximum values; Hyperfast diode



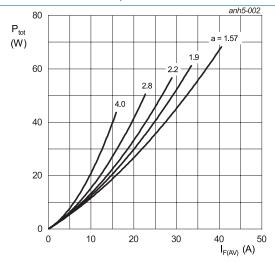
a = form factor =  $I_{F(RMS)}/I_{F(AV)}$  $V_o$  = 1.403 V;  $R_s$  = 0.0138  $\Omega$ 

Fig. 2a. Forward power dissipation as a function of average forward current; sinusoidal waveform; maximum values; Hyperfast diode



$$\begin{split} I_{\text{F(AV)}} &= I_{\text{F(RMS)}} \times \sqrt{\delta} \\ V_{\text{o}} &= 0.997 \text{ V; } R_{\text{s}} = 0.0069 \text{ } \Omega \end{split}$$

Fig. 1b. Forward power dissipation as a function of average forward current; square waveform; maximum values; Standard diode



a = form factor =  $I_{F(RMS)}/I_{F(AV)}$  $V_o$  = 0.997 V;  $R_s$  = 0.0069  $\Omega$ 

Fig. 2b. Forward power dissipation as a function of average forward current; sinusoidal waveform; maximum values; Standard diode

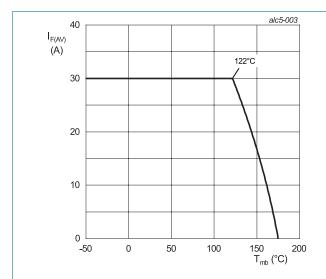


Fig. 3a. Forward current as a function of mounting base temperature; maximum values; Hyperfast diode

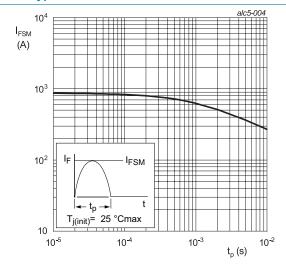


Fig. 4a. Non-repetitive peak forward current as a function of pulse width; sinusoidal waveform; maximum values; Hyperfast diode

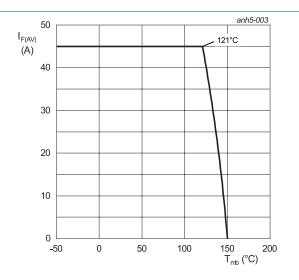


Fig. 3b. Forward current as a function of mounting base temperature; maximum values; Standard diode

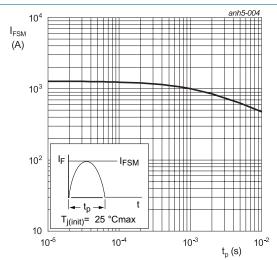
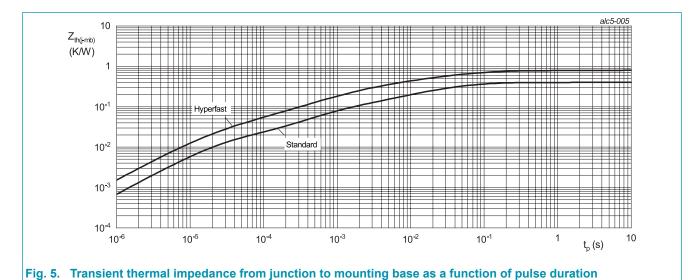


Fig. 4b. Non-repetitive peak forward current as a function of pulse width; sinusoidal waveform; maximum values; Standard diode

## 9. Thermal characteristics

#### **Table 6. Thermal characteristics**

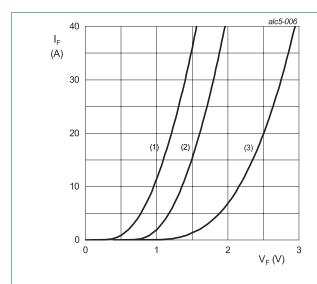
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
fro	thermal resistance from junction to	Hyperfast diode with heatsink compound; Fig. 5	-	-	0.8	K/W
	mounting base	Standard diode with heatsink compound; Fig. 5	-	-	0.4	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient free air	in free air	-	45	-	K/W



# 10. Characteristics

### Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	racteristics			31		
V <sub>F</sub>	forward current	I <sub>F</sub> = 30 A; T <sub>j</sub> = 25 °C; <u>Fig. 6a</u>	-	2	2.75	V
		I <sub>F</sub> = 30 A; T <sub>j</sub> = 150 °C; <u>Fig. 6a</u>	-	1.38	1.8	V
I <sub>R</sub>	reverse current	V <sub>R</sub> = 600 V; T <sub>j</sub> = 25 °C	-	-	10	μΑ
		V <sub>R</sub> = 600 V; T <sub>j</sub> = 150 °C	-	-	1	mA
Dynamic	characteristics					
t <sub>rr</sub>	reverse recovery time	$I_F = 1 \text{ A}; V_R = 30 \text{ V}; dI_F/dt = 200 \text{ A/}\mu\text{s};$ $T_j = 25 \text{ °C}; Fig. 7$	-	18	22	ns
		$I_F = 30 \text{ A}; V_R = 200 \text{ V}; dI_F/dt = 200 \text{ A}/\mu\text{s};$ $T_j = 25 \text{ °C}; Fig. 7$	-	35	50	ns
		$I_F = 30 \text{ A}; V_R = 200 \text{ V}; dI_F/dt = 200 \text{ A/}\mu\text{s};$ $T_j = 125 \text{ °C}; Fig. 7$	-	70	-	ns
		$I_F = 30 \text{ A}; V_R = 400 \text{ V}; dI_F/dt = 500 \text{ A/}\mu\text{s};$ $T_j = 25 \text{ °C}; Fig. 7$	-	29	-	ns
I <sub>RM</sub> peak reverse reco	peak reverse recovery current	$I_F = 30 \text{ A}; V_R = 200 \text{ V}; dI_F/dt = 200 \text{ A/}\mu\text{s};$ $T_j = 25 \text{ °C}; Fig. 7$	-	3.5	7	А
		$I_F = 30 \text{ A}; V_R = 200 \text{ V}; dI_F/dt = 200 \text{ A/}\mu\text{s};$ $T_j = 125 \text{ °C}; Fig. 7$	-	7.6	-	А
$Q_r$	reverse charge	$I_F = 30 \text{ A}; V_R = 200 \text{ V}; dI_F/dt = 200 \text{ A/}\mu\text{s};$ $T_j = 25 \text{ °C}; Fig. 7$	-	50	-	nC
		$I_F = 30 \text{ A}; V_R = 200 \text{ V}; dI_F/dt = 200 \text{ A/}\mu\text{s};$ $T_j = 125 \text{ °C}; Fig. 7$	-	280	-	nC
E <sub>as</sub>	non-repetitive avalanche energy	$I_R = 0.5 \text{ A}; L = 5 \text{ mH}; T_{j(init)} = 25 \text{ °C}$	-	0.625	-	mJ
$V_{FRM}$	forward recovery voltage	$I_F = 10 \text{ A}; \text{ d}I_F/\text{d}t = 10 \text{ A}/\mu\text{s}; T_j = 25 °C; Fig. 8}$	-	-	2	V
			·			
Standard	Recovery Diode					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	racteristics					_
$V_{F}$	forward current	I <sub>F</sub> = 45 A; T <sub>j</sub> = 25 °C; <u>Fig. 6b</u>	-	1.2	1.4	V
		I <sub>F</sub> = 45 A; T <sub>j</sub> = 150 °C; <u>Fig. 6b</u>	-	1.1	1.3	V
I <sub>R</sub>	reverse current	V <sub>R</sub> = 1600 V; T <sub>j</sub> = 25 °C	-	-	10	μΑ
		V <sub>R</sub> = 1600 V; T <sub>j</sub> = 150 °C	-	-	1.5	mA



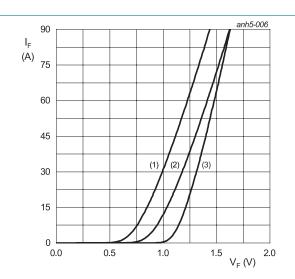
 $V_o$  = 1.403 V;  $R_s$  = 0.0138  $\Omega$ 

(1)  $T_j = 150$  °C; typical values

(2) T<sub>j</sub> = 150 °C; maximum values

(3) T<sub>i</sub> = 25 °C; maximum values

Fig. 6a. Forward current as a function of forward voltage; Hyperfast diode



 $V_o$  = 0.997 V;  $R_s$  = 0.0069  $\Omega$ 

(1) T<sub>j</sub> = 150 °C; typical values

(2)  $T_j = 150$  °C; maximum values

(3)  $T_j = 25$  °C; maximum values

Fig. 6b. Forward current as a function of forward voltage; Standard diode

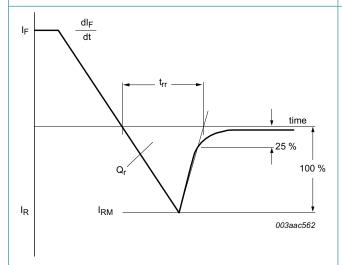


Fig. 7. Reverse recovery definitions; ramp recovery

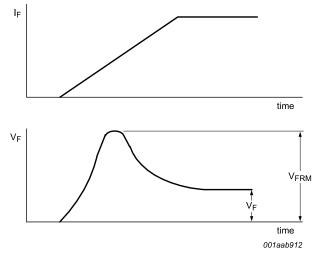
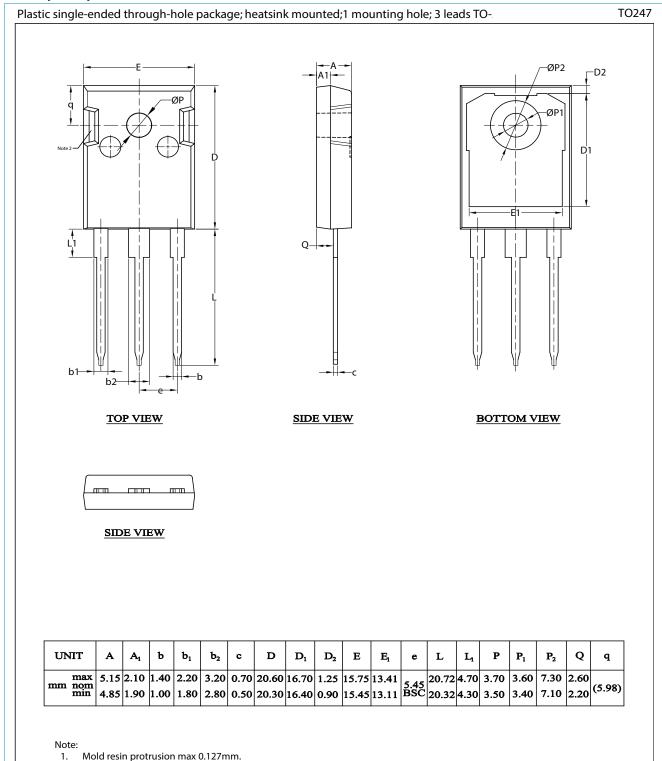


Fig. 8. Forward recovery definitions

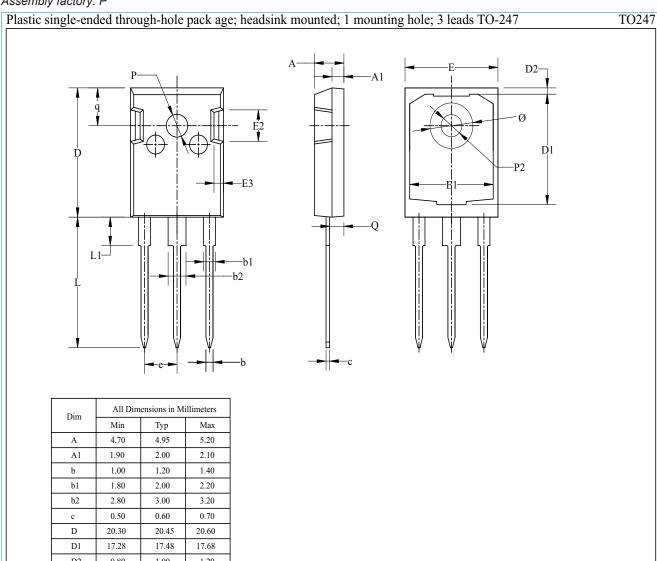
# 11. Package outline

Assembly factory: L



Metal exposed with Sn plating.

## Assembly factory: P



A	4.70	4.95	5.20
A1	1.90	2.00	2.10
b	1.00	1.20	1.40
b1	1.80	2.00	2.20
b2	2.80	3.00	3.20
с	0.50	0.60	0.70
D	20.30	20.45	20.60
D1	17.28	17.48	17.68
D2	0.80	1.00	1.20
Е	15.45	15.60	15.75
E1	13.82	14.02	14.22
E2	4.80	5.00	5.20
E3	1.40	1.60	1.80
e		5.45 BSC	
L	20.40	20.65	20.90
L1	4.25	4.50	4.75
P2	3.40	3.50	3.60
P	3.50	3.60	3.70
Q	2.20	2.40	2.60
q	5.78	5.98	6.18
Ø	7.10	7.19	7.30

# 12. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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